

**Performance comparison of hybrid
sputtering/evaporation $\text{CuIn}_{1-x}\text{Ga}_x\text{Se}_2$ solar cells with
different transparent conducting oxide window layers**

A.F da Cunha ^{a,*}, F.Kurdeasu ^a,
D.Rudmann ^b, P.M.P.Salome ^a



*Southern
Taiwan
University*

指導教授: 高至誠

學生 : 邱暉承

Outline

- Introduction
- Experimental details
- Results and Discussion
 - SEM/EDX measurements
 - Transmission coefficients
 - I-V measurements
- Conclusion

Introduction

- A possible approach is the adaptation of existing production equipment such as sputtering systems. The methods employed for Cu(In,Ga)Se_2 absorber layer deposition are coevaporation, rapid thermal processing (RTP) and H_2Se selenization of Cu(Ga)/In metallic layers.
- For this purpose we have carried out a comparative study of the performance of solar cells with the usual $i\text{-ZnO/ZnO:Al}$ and ITO window layers.

Experimental details

TCO

i-ZnO/ZnO:Al or ITO

CdS

50nm (CBD)

CIGS

Sputter/evaporation

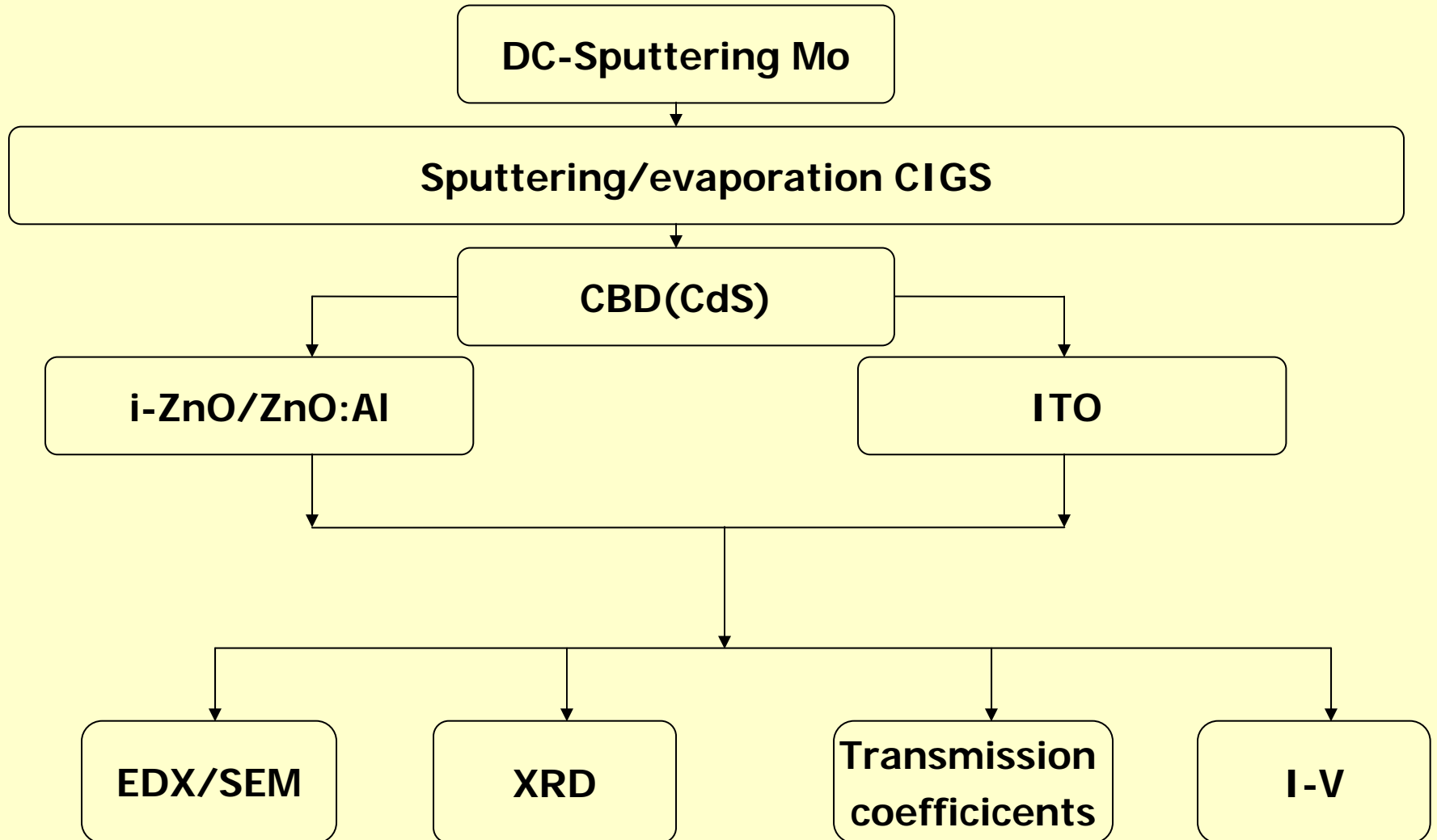
Mo

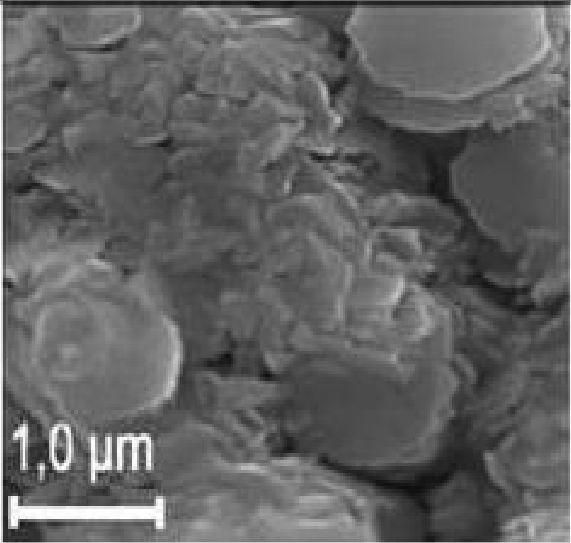
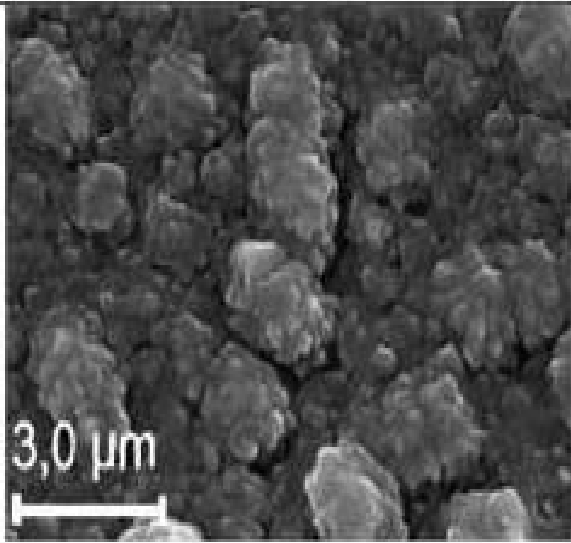
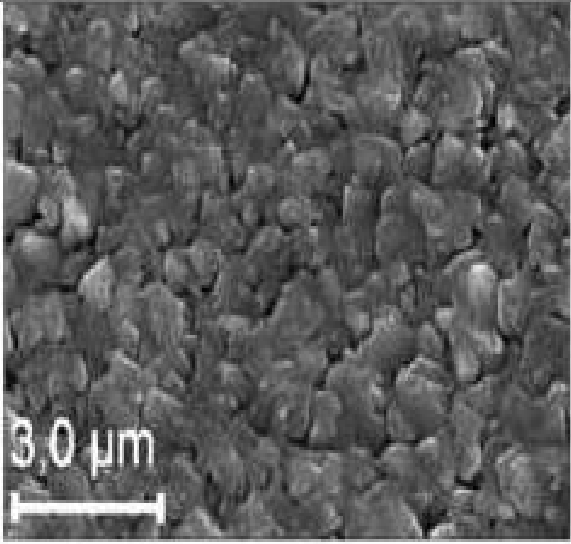
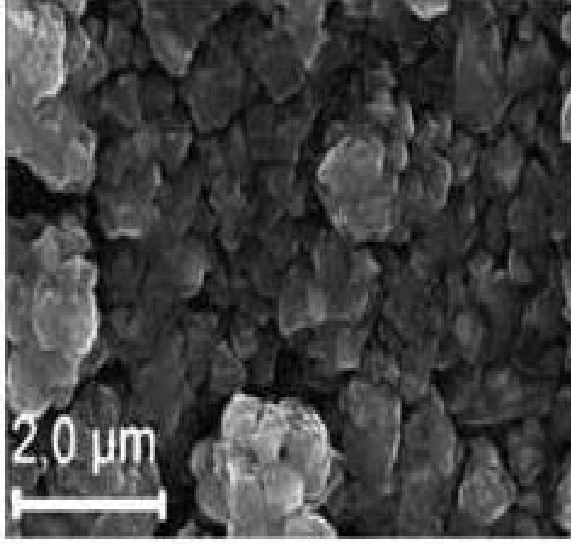
0.5 μ m (DC-Sputtering)

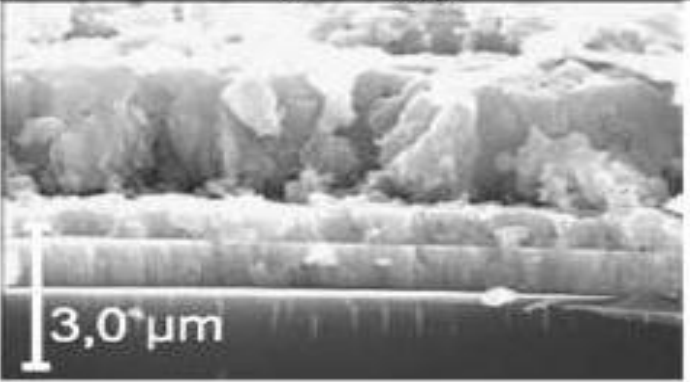
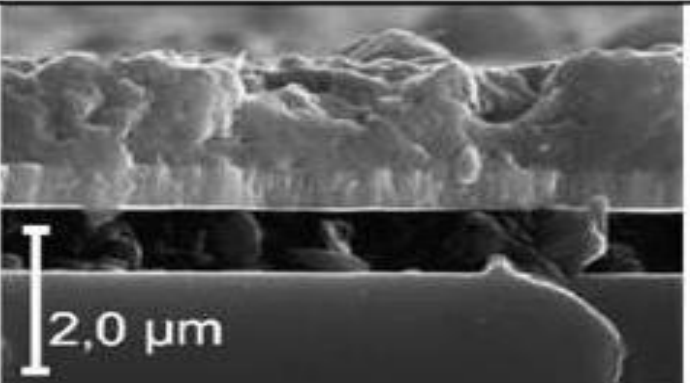
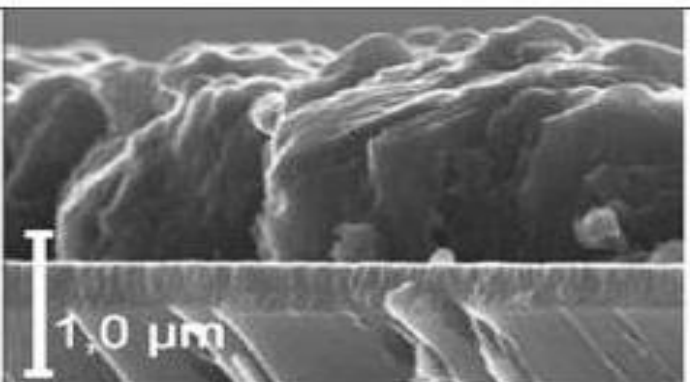
Glass

soda lime glass

Experimental details



Sample	Surface morphology		
1	 <p>SEM image showing the surface morphology of Sample 1. The surface is covered with large, irregular, plate-like structures. A scale bar in the bottom left corner indicates 1,0 μm.</p>	3	 <p>SEM image showing the surface morphology of Sample 3. The surface is covered with smaller, more rounded, and irregular structures. A scale bar in the bottom left corner indicates 3,0 μm.</p>
2	 <p>SEM image showing the surface morphology of Sample 2. The surface is covered with small, irregular, and somewhat rounded structures. A scale bar in the bottom left corner indicates 3,0 μm.</p>	4	 <p>SEM image showing the surface morphology of Sample 4. The surface is covered with small, irregular, and somewhat rounded structures. A scale bar in the bottom left corner indicates 2,0 μm.</p>

Sample	Cross-section morphology
1	 <p data-bbox="873 107 1566 485">Scanning electron micrograph (SEM) showing the cross-section morphology of Sample 1. The image displays a layered structure with a rough, porous top layer and a smoother bottom layer. A vertical scale bar in the bottom left corner indicates a length of 3,0 μm.</p>
2	 <p data-bbox="873 542 1566 921">Scanning electron micrograph (SEM) showing the cross-section morphology of Sample 2. The image displays a porous, irregular structure with a rough top surface and a smoother bottom surface. A vertical scale bar in the bottom left corner indicates a length of 2,0 μm.</p>
3	 <p data-bbox="873 978 1566 1356">Scanning electron micrograph (SEM) showing the cross-section morphology of Sample 3. The image displays a highly porous, irregular structure with a rough top surface and a smoother bottom surface. A vertical scale bar in the bottom left corner indicates a length of 1,0 μm.</p>

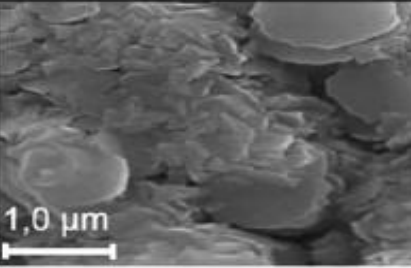
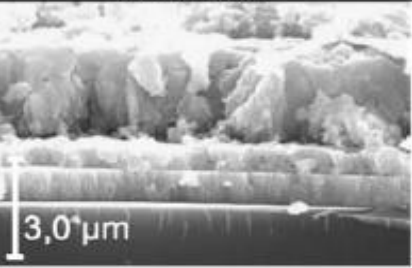
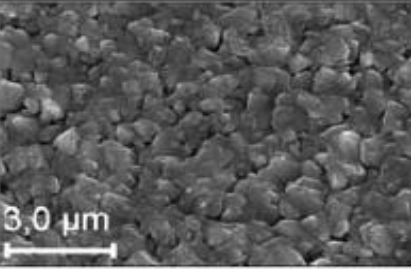
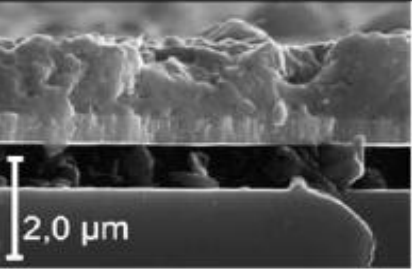
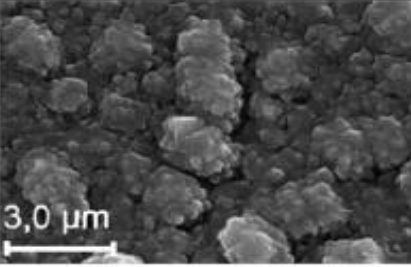
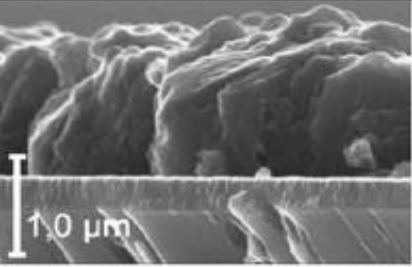
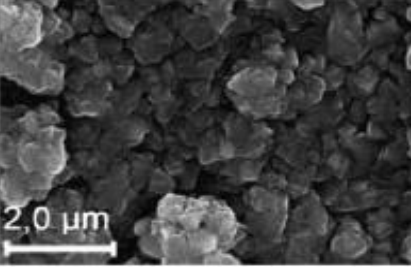
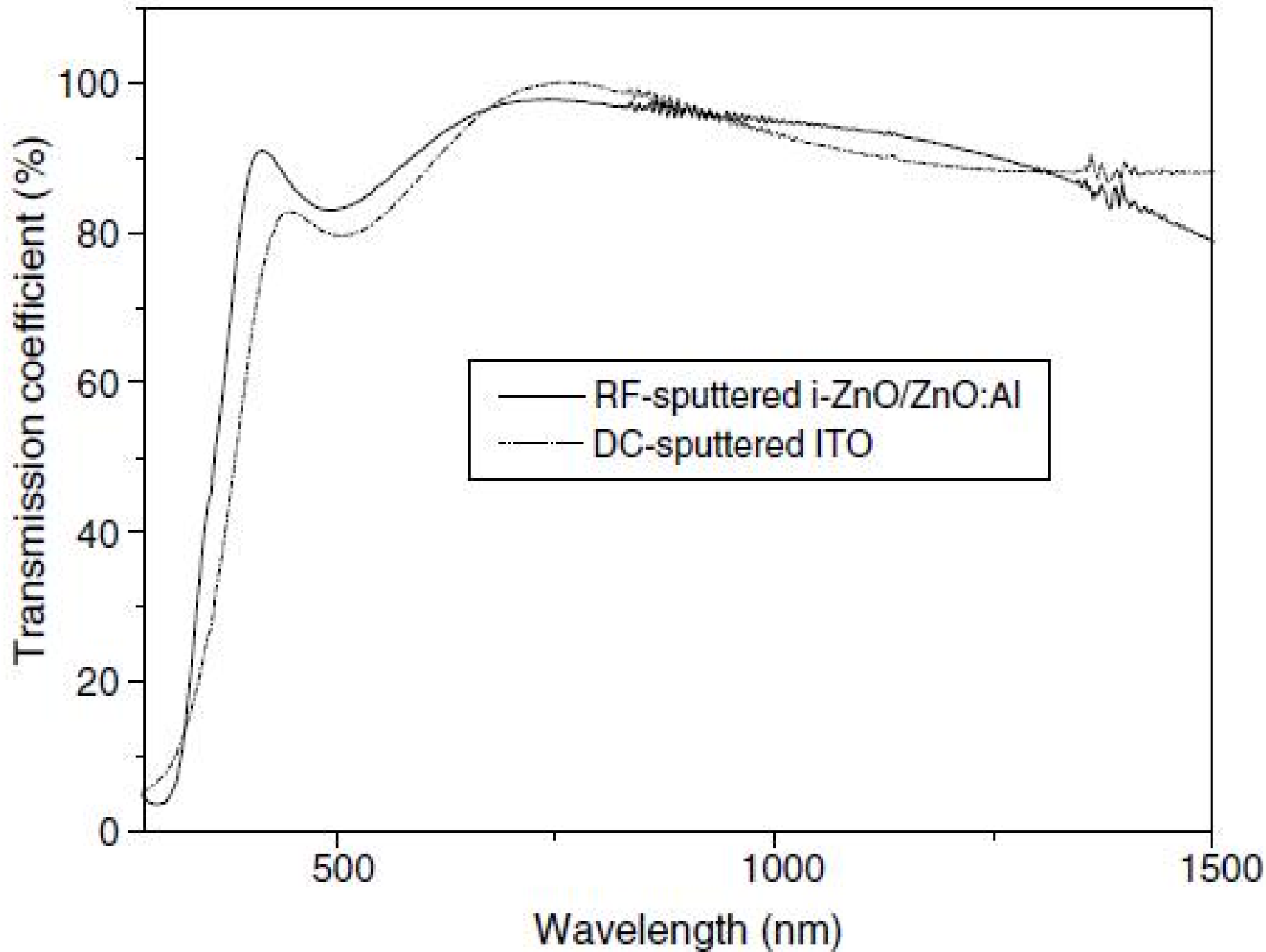
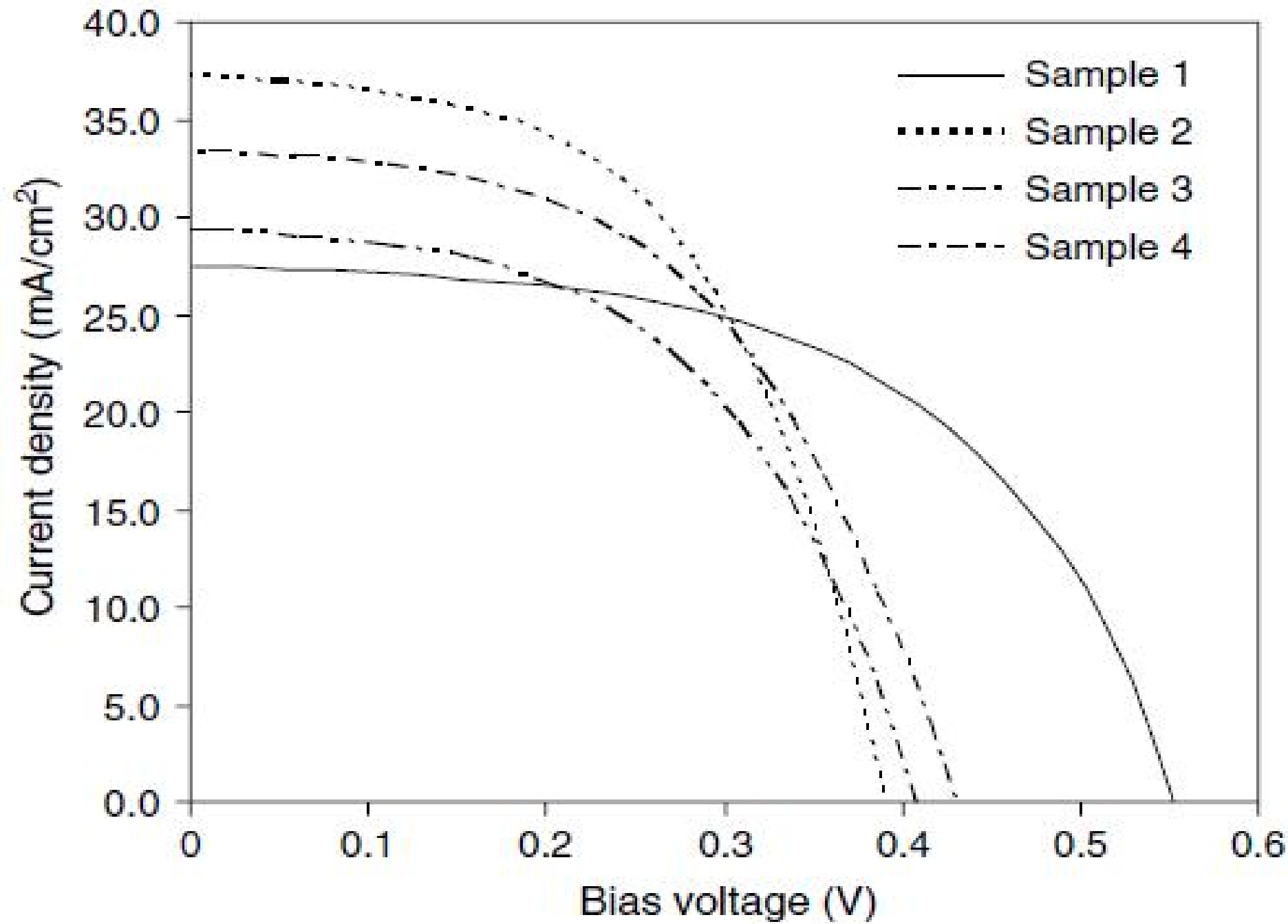
Sample	Surface morphology	Cross-section morphology
1		
2		
3		
4		

Fig. 1. SEM surface (left) and cross-section (right) pictures of the CIGS solar cell absorber layers. The surface pictures show that the roughness of the CIGS absorbers vary from sample to sample for similar deposition conditions. The cross-section pictures show from top to bottom the CIGS layer, the Mo layer and the glass substrate.





Results and Discussion

sample	(cm ⁻³) Absorber carrier density	Cell series resistance (Ω)	V _{oc} (mV)	J _{sc} (mA/cm ²)	F.F.(%)	Cell efficiency (%)
1	2.1×10 ¹⁶	22.2	552.3	27.5	54.8	8.3
2	1.2×10 ¹⁵	11.3	389	37	54.3	7.8
3	1.7×10 ¹⁶	27.5	407.4	29.3	52.1	6.3
4	1.6×10 ¹⁵	40.4	428.8	33.5	51.6	7.4

Conclusion

- Solar cells have been prepared and studied with CIGS prepared by a two-stage sputtering/evaporation method and finished with i-ZnO/ZnO:Al and ITO layers.
- The room temperature DC-magnetron sputtering of ITO has been optimized to obtain properties identical to the more commonly used i-ZnO/ZnO:Al window layer.

Thanks for your attention